

Scanning Electron Microscopes (SEM) on campus

1. Arlene Oatway, Bio Sciences Dept.
CW225H Biological Sciences Bldg
780-248-1077 arlene.oatway@ualberta.ca
Variable pressure SEM, thus samples may need to be coated, no EDX
Bring a signed indent.
2. Scanning Electron Microscope Laboratory
2-17C Earth and Atmospheric Sciences Bldg
(780) 492-5764
<http://www.eas.ualberta.ca/sem/>
Field Emission (high resolution) SEM with EDX
3. Dimitre Karpuzov: Manager of ACSES (Alberta Center of Surface Engineering and Science) group karpuzov@ualberta.ca
Dr. Doug Ivey: Director ACSES group doug.ivey@ualberta.ca
(780) 492-1246 or (780) 492-2150
Main Lab L2-356 CCIS (Centennial Center of Interdisciplinary Science) Bldg
http://www.ualberta.ca/ACSES/ACSES3/analysis_request.htm (fill out the Assisted Service Form)
Scanning Auger Microscope that has Secondary Electron capability, and ESC installed.
Also SIMS, XPS, AFM
4. Tina Barker: SEM Technician
174 Chemical-Materials Engineering Bldg
(780) 492-2859 Tina.Barker@ualberta.ca
5. Sergei Matveev
Room B10, Earth and Atmospheric Sciences Bldg.
Telephone: 780-492-3191
Notes – Electron Microprobe with both EDX and WDX
6. Daniel Salamon, NINT (National Institute for Nanotechnology).
Email: Daniel.Salamon@nrc-cnrc.gc.ca
Website : http://nint-innt.nrc-cnrc.gc.ca/facilities/micro/index_e.html
Note - SEM with EDX, TEM with EELS. Please refer to website for more details.